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Application/Control No.	Applicant(s)/Patent under Reexamination
10/532,864	KANO ET AL.
Examiner	Art Unit
Hau V. Phan	3618

SEARCHED			
Class	Subclass	Date	Examiner
180	65.1 65.2 65.3 65.4	12/6/2007	HP
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903	.951	12/6/2007	HP
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475	230	12/6/2007	HP
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INTERFERENCE SEARCHED			
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